



CERTIFICATE OF MAILING

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Kristi L. Davidson, Reg. No. 44,643

Date

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:

10/711,649

Filed:

September 29, 2004

Group Art Unit:

1756

Examiner:

Unknown Kohei Kawamura et al.

Applicant: Title:

A METHOD FOR SUPERCRITICAL CARBON DIOXIDE

PROCESSING OF FLUORO-CARBON FILMS

Attorney Docket:

SSIT-114

Confirmation No.:

5648

Cincinnati, Ohio 45202

November 18, 2005

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

In accordance with the duty of candor and good faith imposed by 37 C.F.R. §1.56, and means of complying therewith according to 37 C.F.R. §\$1.97 and 1.98, the references listed on the attached Form PTO-1449 are called to the attention of the United States Patent and Trademark Office in connection with the above-identified patent application. Because the requirement

Application Serial No. 10/711,649
Supplemental Information Disclosure Statement submitted November 18, 2005
from International Search Report of PCT/US2005/013885

(37 C.F.R. §1.98(a)(2)(i)) for submitting copies of U.S. patents and published applications has been waived, copies of only the foreign cited references and/or other documents are enclosed herewith. Applicants have also enclosed a copy of the International Search Report listing these references, which was received in the counterpart foreign application for related Patent Application Serial No. 10/881,456. It is noted that International Publication No. WO 01/33613 has already been cited in this application. It is further noted that U.S. Patent Publication No. US 2003/0150559 has now issued as U.S. Patent No. 6,926,798, and therefore is referenced as such on the Form PTO-1449.

It is submitted that the cited references do not disclose or render obvious the subject matter claimed in the present application.

Certifications under 37 C.F.R. § 1.97(e) and § 1.704(d)

Each item of information contained in the information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

Each item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart application and to the knowledge of the person signing the certification after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in 37 C.F.R. § 1.56(c) more than thirty days prior to the filing of the information disclosure statement.

Application Serial No. 10/711,649 Supplemental Information Disclosure Statement submitted November 18, 2005 from International Search Report of PCT/US2005/013885

Applicants do not believe that any fees are due in connection with this submission. However, if such petition is due or any fees are necessary, the Commissioner may consider this to be a request for such and charge any necessary fees to Deposit Account No. 23-3000.

Respectfully submitted,

WOOD, HERRON & EVANS, L.L.P.

By:_

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OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)

A.R Jones et al., <u>HF Etchant Solutions in Supercritical Carbon Dioxide for "Dry" Etch Processing of Microelectronic Devices, Chem Mater.</u>, Vol. 15, 2003, pp. 2867-2869

A.S Gangopadhyay et al., <u>Supercritical CO, Treatments for Semiconductor Applications</u>, Mat. Res. Soc. Symp. Proc., Vol. 812, 2004, pp. F4.6.1-F4.6.6

A.T DeYoung et al., <u>Methods and Compositions for Etch Cleaning Microelectronic Substrates in Carbon Dioxide</u>, US 2004/0045588 A1; Publication Date 03/11/2004; Filed 09/10/2003; U.S. Class 134/26

EXAMINER

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DATE CONSIDERED

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